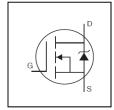


HEXFET® Power MOSFET

Features

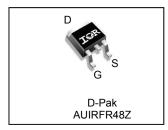
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- · Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified *



V _{DSS}	55V
R _{DS(on)} max.	11mΩ
D (Silicon Limited)	62A
D (Package Limited)	42A

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

Base next number Backage Type		Standard Pack	•	Orderable Part Number			
Base part number	Package Type	Form Quant		Form Quanti		Orderable Part Number	
AUIRFR48Z	D. Dak	Tube	75	AUIRFR48Z			
AUIRFR40Z	D-Pak	Tape and Reel Left	3000	AUIRFR48ZTRL			

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	62	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	44	Α
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	42	
I _{DM}	Pulsed Drain Current ①	250	
P _D @T _C = 25°C	Maximum Power Dissipation	91	W
	Linear Derating Factor	0.61	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS} Single Pulse Avalanche Energy (Thermally Limited) ②		74	mJ
E _{AS} (Tested)	Single Pulse Avalanche Energy Tested Value ®	110 r	
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E _{AR}	Repetitive Avalanche Energy ®		mJ
T_J	Operating Junction and -55 to + 175		
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol Parameter		Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		1.64	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ⑦		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

HEXFET® is a registered trademark of Infineon.

2015-12-1

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.054		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		8.86	11	mΩ	V _{GS} = 10V, I _D = 37A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 50\mu A$
gfs	Forward Trans conductance	120			S	$V_{DS} = 25V, I_{D} = 37A$ ③
	Drain to Source Lookage Current			20		$V_{DS} = 55V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			200	n 1	V _{GS} = 20V
IGSS	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	•		-	-		
Q_g	Total Gate Charge		40	60		I _D = 37A
Q_gs	Gate-to-Source Charge		11		nC	V _{DS} = 44V
Q_{gd}	Gate-to-Drain Charge		15			V _{GS} = 10V3
$t_{d(on)}$	Turn-On Delay Time		15			$V_{DD} = 28V$
t _r	Rise Time	_	61		no	I _D = 37A
$t_{d(off)}$	Turn-Off Delay Time		40		ns	$R_G = 12\Omega$
t _f	Fall Time		35			V _{GS} = 10V③
L _D	Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance		7.5			from package and center of die contact
C _{iss}	Input Capacitance		1720			$V_{GS} = 0V$
C_{oss}	Output Capacitance		290			$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance		160		рF	f = 1.0MHz
C_{oss}	Output Capacitance		1000		рΓ	$V_{GS} = 0V$, $V_{DS} = 1.0V$ $f = 1.0MHz$
Coss	Output Capacitance		230			$V_{GS} = 0V$, $V_{DS} = 44V$ $f = 1.0MHz$
Coss eff.	Effective Output Capacitance		360			V_{GS} = 0V, V_{DS} = 0V to 44V $\textcircled{4}$

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			37		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			250		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 37A, V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		20	40	ns	$T_J = 25^{\circ}C$, $I_F = 37A$, $V_{DD} = 28V$
Q_{rr}	Reverse Recovery Charge		14	28	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population, starting $T_J = 25$ °C, L = 0.11mH, R_G = 25Ω, I_{AS} = 37A, V_{GS} =10V.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994

 \otimes R₀ is measured at T_J approximately 90°C.



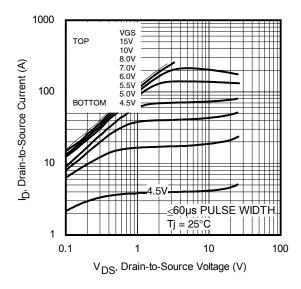


Fig. 1 Typical Output Characteristics

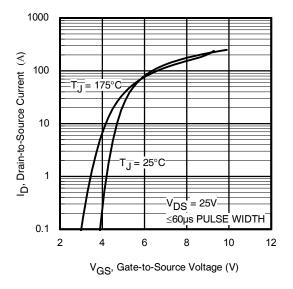


Fig. 3 Typical Transfer Characteristics

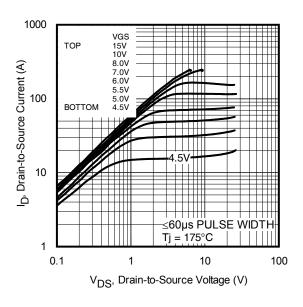


Fig. 2 Typical Output Characteristics

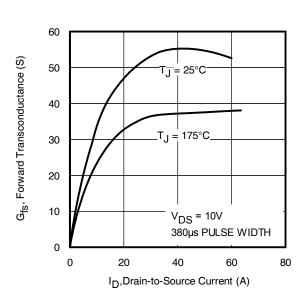


Fig. 4 Typical Forward Trans conductance Vs. Drain Current



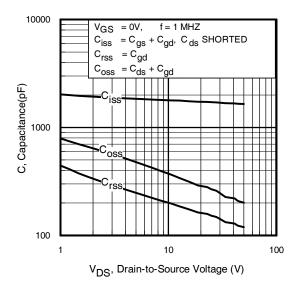


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

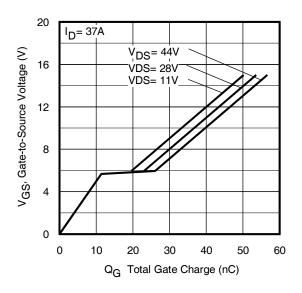


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

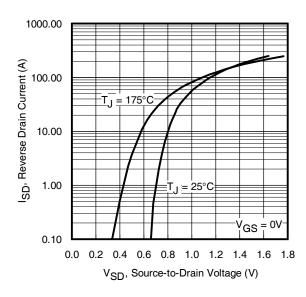


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

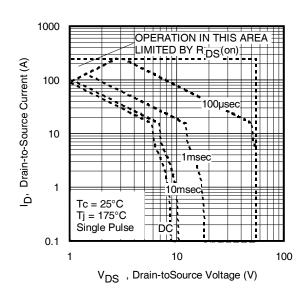
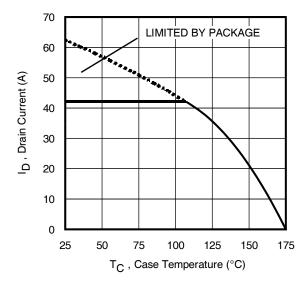


Fig 8. Maximum Safe Operating Area

4





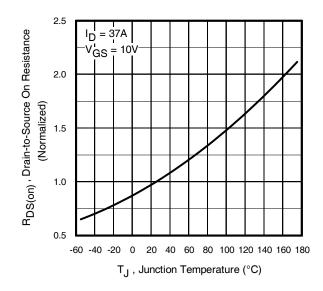


Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10. Normalized On-Resistance Vs. Temperature

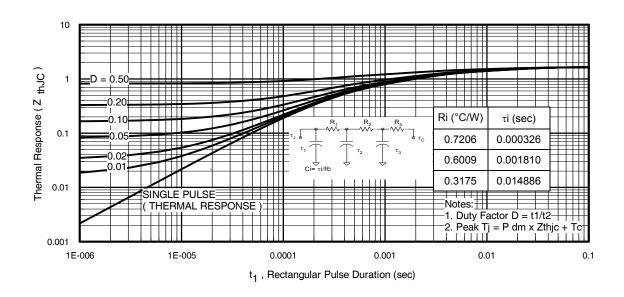


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



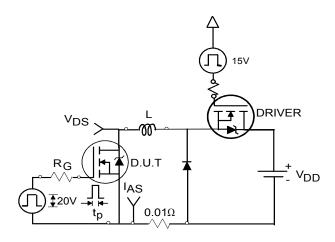


Fig 12a. Unclamped Inductive Test Circuit

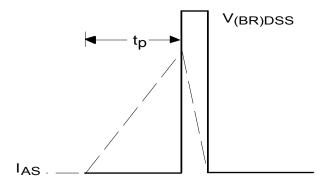


Fig 12b. Unclamped Inductive Waveforms

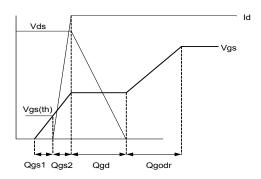


Fig 13a. Gate Charge Waveform

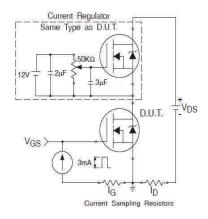


Fig 13b. Gate Charge Test Circuit

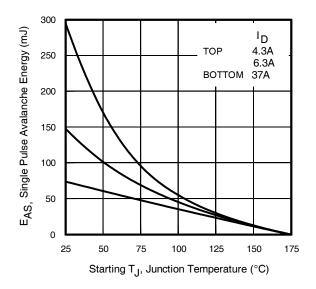


Fig 12c. Maximum Avalanche Energy vs. Drain Current

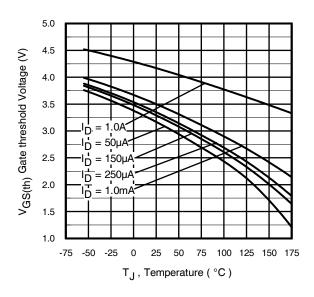


Fig 14. Threshold Voltage Vs. Temperature



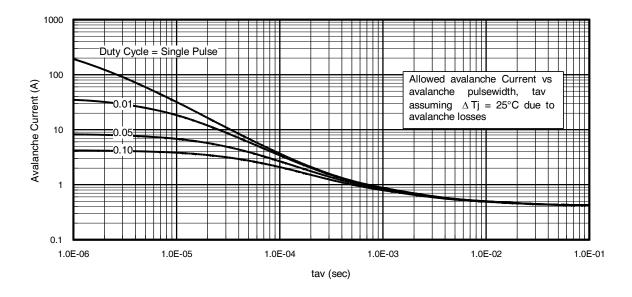


Fig 15. Typical Avalanche Current Vs. Pulse width

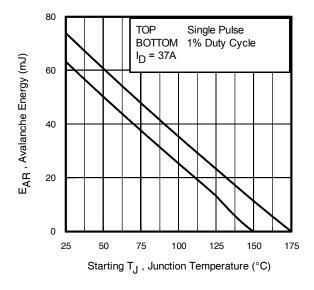


Fig 16. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 15, 16:

(For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{imax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



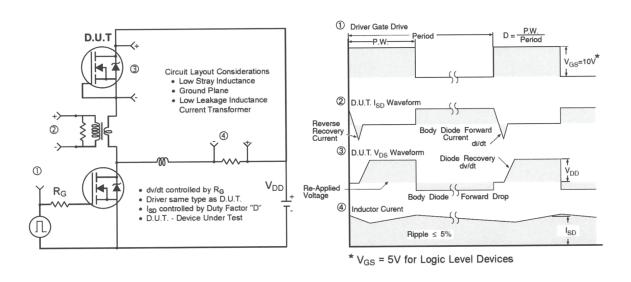


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

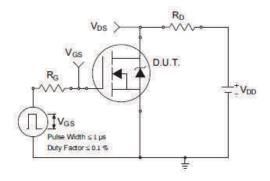


Fig 18a. Switching Time Test Circuit

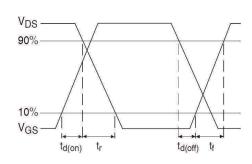
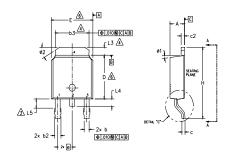


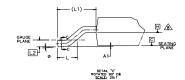
Fig 18b. Switching Time Waveforms

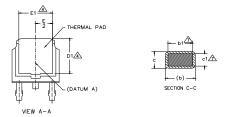


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- Limited Dimension D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S					N	
Y M	DIMENSIONS					
B	MILLIM	ETERS	INC	HES	O T E S	
L	MIN.	MAX.	MIN.	MAX.	S	
Α	2.18	2.39	.086	.094		
A1	-	0.13	-	.005		
b	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	7	
b2	0.76	1.14	.030	.045		
b3	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
е	2.29	BSC	.090	BSC		
Н	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74	BSC	.108	REF.		
L2	0.51	BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	-	1.02	-	.040		
L5	1.14	1.52	.045	.060	3	
ø	0.	10°	0,	10°		
ø1	0,	15*	0,	15*		
ø2	25*	35°	25*	35*		

LEAD ASSIGNMENTS

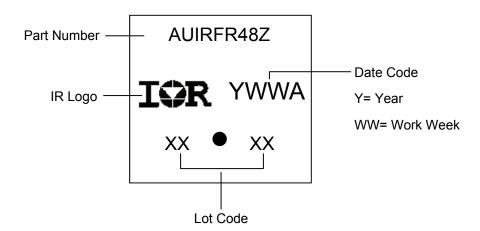
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER 4.- COLLECTOR

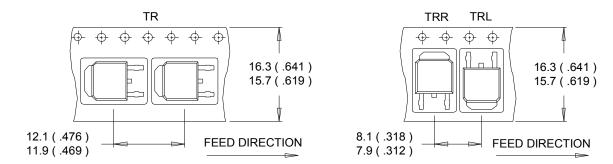
D-Pak (TO-252AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

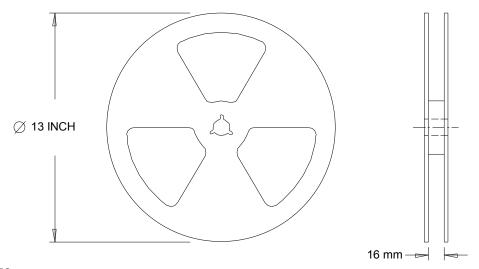


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

	ion inioniation						
		Automotive					
		(per AEC-Q101)					
Qualificat	ion Level	Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.					
Moisture	Moisture Sensitivity Level D-Pak MSL1						
			Class M4 (+/-425V) [†]				
	Machine Model	AEC-Q101-002					
FOD	Lluman Dady Madal	Class H1B (+/-1000V) †					
ESD	Human Body Model	AEC-Q101-001					
Charged Device Model		Class C5 (+/-1125V) [†]					
		AEC-Q101-005					
RoHS Co	mpliant		Yes				

[†] Highest passing voltage.

Revision History

Date	Comments		
12/1/2015	Updated datasheet with corporate template		
12/1/2013	Corrected ordering table on page 1.		

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